TOSHIBA CCD Linear Image Sensor CCD (Charge Coupled Device)

TCD1304DG



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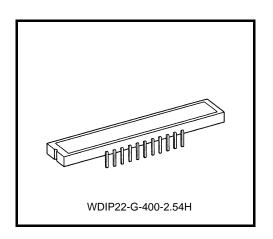
The TCD1304DG is a high sensitive and low dark current 3648 elements CCD linear image sensor.

The device consist of sensitivity CCD chip.

The TCD1304DG has electronic shutter function (ICG). Electronic shutter function can keep always output voltage constant that vary with intensity of lights.

Features

- Number of Image Sensing Elements: 3648 elements
- Image Sensing Element Size: 8 μm by 200 μm on 8 μm center
- · Photo Sensing Region: High sensitive PN photodiode
- Power Supply Voltage: 3.0 V (min)Internal Circuit: CCD drive circuit
- Package: 22 pin CERDIP
- Function: Electronic shutter, Sample and hold circuit



ABSOLUTE MAXIMUM RATINGS (Note 1)

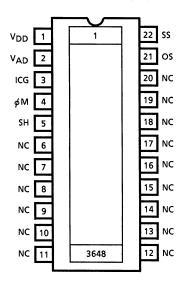
| Characteristic | Symbol | Rating | Unit |
|---------------------------------|------------------|--------------|------|
| Master clock pulse voltage | $V_{\phi M}$ | | |
| Shift pulse voltage | VsH | | |
| Integration clear pulse voltage | Vicg | −0.3 to +7.0 | V |
| Digital power supply voltage | V _{DD} | | |
| Analog power supply voltage | V _{AD} | | |
| Operating temperature | T _{opr} | −25 to +60 | °C |
| Storage temperature | T _{stg} | −40 to +100 | °C |

Note 1: All voltages are with respect to SS terminals (ground).

None of the ABSOLUTE MAXIMUM RATINGS must be exceeded, even instantaneously.

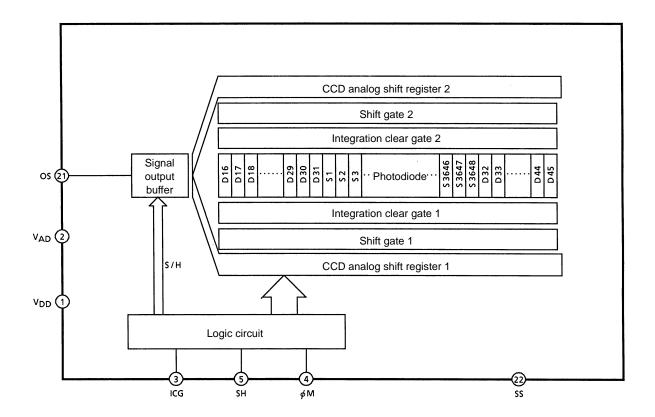
If any one of the ABSOLUTE MAXIMUM RATINGS is exceeded, the electrical characteristics, reliability and life time of the device cannot be guaranteed. If the ABSOLUTE MAXIMUM RATINGS are exceeded, the device can be permanently damaged or degraded. Create a system design in such a manner that any of the ABSOLUTE MAXIMUM RATINGS will not be exceeded under any circumstances.

Pin Connections (top view)





Circuit Diagram



Pin Names

| Pin No. | Symbol | Name | Pin No. | Symbol | Name |
|---------|--------|------------------------|---------|--------|----------------|
| 1 | VDD | Power supply (Digital) | 22 | SS | Ground |
| 2 | VAD | Power supply (Analog) | 21 | os | Output signal |
| 3 | ICG | Integration clear gate | 20 | NC | Non connection |
| 4 | φМ | Master clock | 19 | NC | Non connection |
| 5 | SH | Shift gate | 18 | NC | Non connection |
| 6 | NC | Non connection | 17 | NC | Non connection |
| 7 | NC | Non connection | 16 | NC | Non connection |
| 8 | NC | Non connection | 15 | NC | Non connection |
| 9 | NC | Non connection | 14 | NC | Non connection |
| 10 | NC | Non connection | 13 | NC | Non connection |
| 11 | NC | Non connection | 12 | NC | Non connection |



Optical/Electrical Characteristics

Ta = 25°C, VAD = VDD = 4.0 V, V_{ϕ} = 4.0 V (pulse), fDATA = 0.5 MHz, tINT (integration time) = 10 ms, light source = daylight fluorescent lamp

| Characteristic | Symbol | Min | Тур. | Max | Unit | Note |
|---------------------------------|---------|-----|-------|-----|--------|-------------------------|
| Sensitivity | R | 110 | 160 | _ | V/lx·s | _ |
| Photo response non uniformity | PRNU | _ | _ | 10 | % | (Note 2) |
| Register imbalance | RI | _ | _ | 3 | % | (Note 3) |
| Saturation output voltage | VSAT | 450 | 600 | _ | mV | (Note 4) |
| Dark signal voltage | VMDK | _ | 2 | 5 | mV | (Note 5) |
| Total transfer effeiciency | TTE | 92 | 95 | _ | % | _ |
| Dynamic range | DR | _ | 300 | _ | _ | (Note 6) |
| Saturation exposure | SE | _ | 0.004 | _ | lx⋅s | (Note 7) |
| DC power dissipation | PD | _ | 25 | 75 | mW | _ |
| DC output signal voltage | Vos | 1.5 | 2.5 | 3.5 | V | (Note 8) |
| Output impedance | ZO | _ | 0.5 | 1.0 | kΩ | _ |
| Image lag of electronic shutter | VLAGICG | _ | _ | 10 | mV | t _{INT} =100µs |

Note 2: PRNU is defined on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature, and the incident light is 50 % of SE (typ.).

$$PRNU = \frac{\Delta X}{\overline{X}} \times 100 \text{ (\%)}$$

 \overline{X} : Average of total signal outputs

 ΔX : The maximum deviation from \overline{X}

Note 3: Register imbalance is defined as follows. Measured with 50 % of SE (typ.).

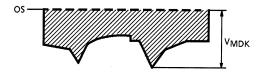
$$RI = \frac{\Delta Y}{\overline{X}} \times 100 \text{ (\%)}$$

 \overline{X} : Average of total signal outputs

 ΔY : | (average of odd signal output) – (average of even signal output) |

Note 4: VSAT is defined as the minimum saturation output voltage of all effective pixels. VAD = VDD = 3.0 V.

Note 5: VMDK is defined as the maximum dark signal voltage of all effective pixels.





Note 6: Definition of DR:

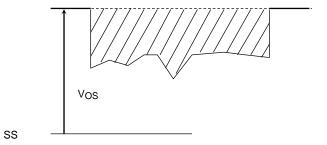
$$DR = \ \frac{V_{SAT}}{V_{MDK}}$$

VMDK is proportional to tINT (integration time). So the shorter integration time makes wider dynamic range.

Note 7: Definition of SE:

$$SE = \frac{V_{SAT}}{R}$$

Note 8: DC output signal voltage is defined as follows.



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Recommended Operating Conditions (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

| Characteristic | | Symbol | Min | Тур. | Max | Unit |
|---------------------------------|-----------|-----------------|-----|------|------|------|
| Montos clock pulso voltago | "H" level | \/ | 3.0 | 4.0 | 5.5 | V |
| Master clock pulse voltage | "L" level | V _{φM} | 0 | 0 | 0.44 | |
| Shift pulse veltage | "H" level | Vou | 3.0 | 4.0 | 5.5 | V |
| Shift pulse voltage | "L" level | Vsh | 0 | 0 | 0.44 | V |
| Integration clear pulse voltage | "H" level | Vice | 3.0 | 4.0 | 5.5 | V |
| Integration clear pulse voltage | "L" level | VICG | 0 | 0 | 0.44 | ď |
| Digital power supply voltage | | V _{DD} | 3.0 | 4.0 | 5.5 | V |
| Analog power supply voltage | | V _{AD} | 3.0 | 4.0 | 5.5 | V |

Note: $V_{AD} = V_{DD}$

max voltage of pulse voltage "H" level = $V_{DD} = V_{AD}$

min voltage of pulse voltage "H" level = VDD - 0.5 V = VAD - 0.5 V

Clock Characteristics (Ta = 25° C) (VAD = VDD ≥ 4.0 V)

For best performance, the device should be used within the Recommended Operating Conditions.

| Characteristic | Symbol | Min | Тур. | Max | Unit |
|------------------------------------|--------|-----|------|-----|------|
| Master clock pulse frequency | fφM | 0.8 | 2.0 | 4.0 | MHz |
| Data rate | fdata | 0.2 | 0.5 | 1.0 | MHz |
| Master clock capacitance | СфМ | _ | 10 | _ | pF |
| Shift gate capacitance | Csh | _ | 600 | _ | pF |
| Integration clear gate capacitance | Cicg | _ | 250 | _ | pF |

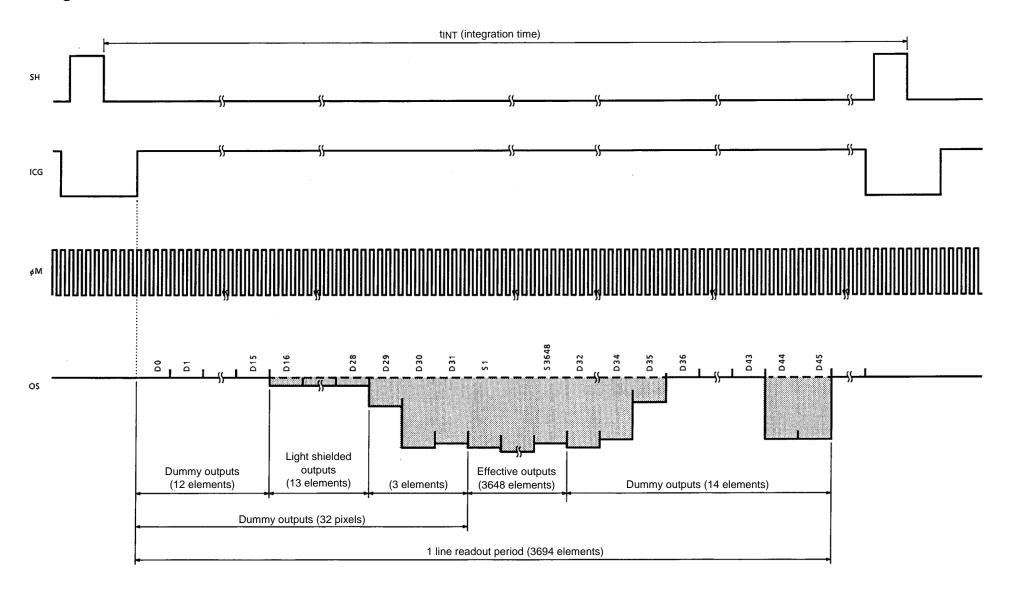
Clock Characteristics (Ta = 25° C) (3.0 V \leq VAD = VDD < 4.0 V)

For best performance, the device should be used within the Recommended Operating Conditions.

| Characteristic | Symbol | Min | Тур. | Max | Unit |
|------------------------------|-------------------------|-----|------|-----|------|
| Master clock pulse frequency | $f_{oldsymbol{\phi} M}$ | 0.8 | 2.0 | 2.4 | MHz |
| Data rate | fdata | 0.2 | 0.5 | 0.6 | MHz |

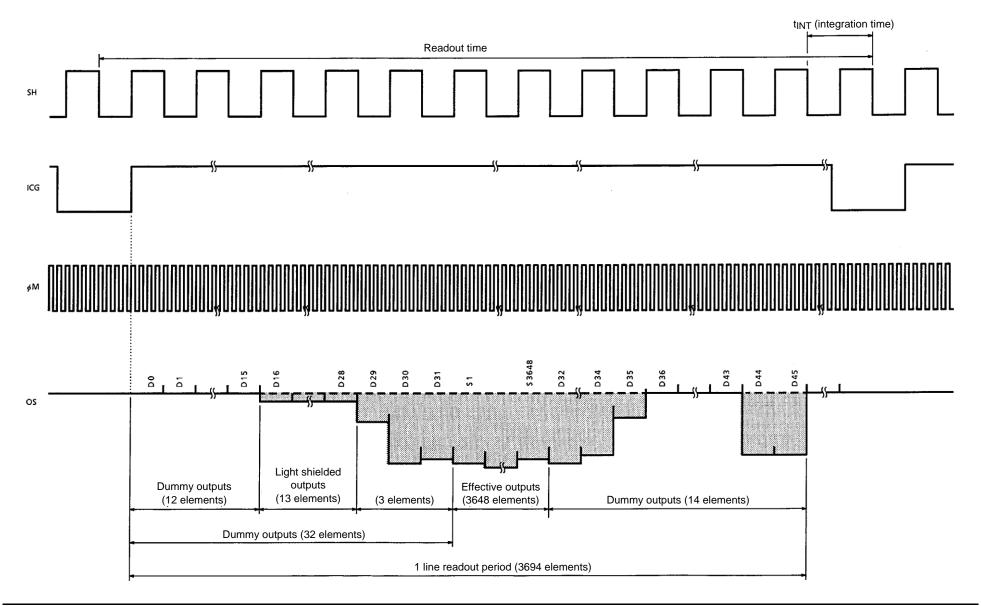


Timing Chart



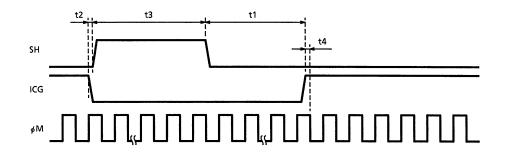
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Timing Chart (Use Electronic Shutter Function)





Timing Requirements



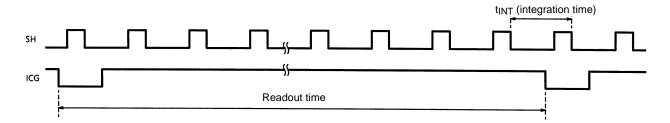
| Characteristic | Symbol | Min | Тур. | Max | Unit |
|------------------------------------|--------|------|------|------|------|
| ICG pulse delay | t1 | 1000 | 5000 | _ | ns |
| Pulse timing of ICG and SH | t2 | 100 | 500 | 1000 | ns |
| SH pulse width | t3 | 1000 | _ | _ | ns |
| Pulse timing of ICG and \$\phi M\$ | t4 | 0 | 20 | * | ns |

^{*:} Keep the ϕM pin "H" level.

Use Electronic Shutter

Pulse timing of SH and ICG

SH cycle = tint



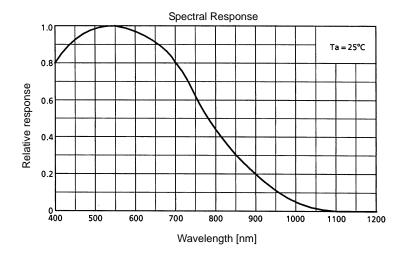
 $tINT (min) = 10 \mu s$

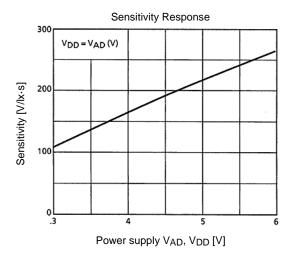
SH pulse width (t3) shold be kept constant.

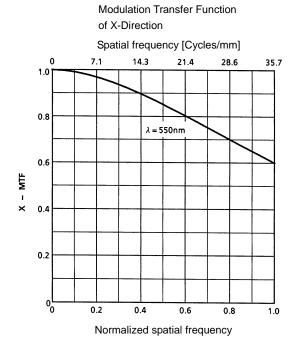
The illumination of light source must be less than 1000 times of the 450 mV output condition at tINT = 10 ms.



Typical Perfomance Curves

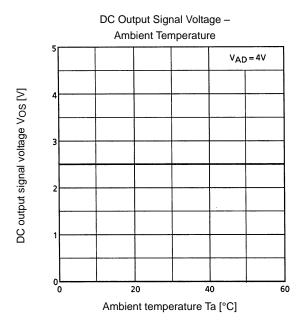


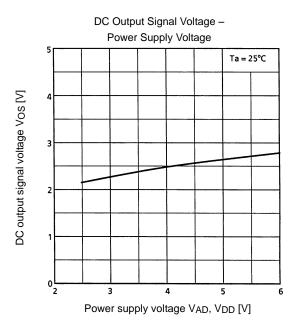


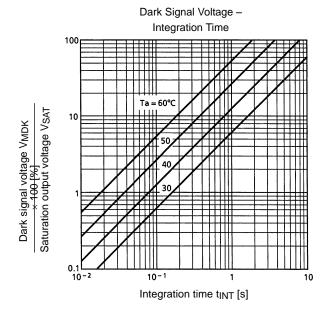




Typical Perfomance Curves

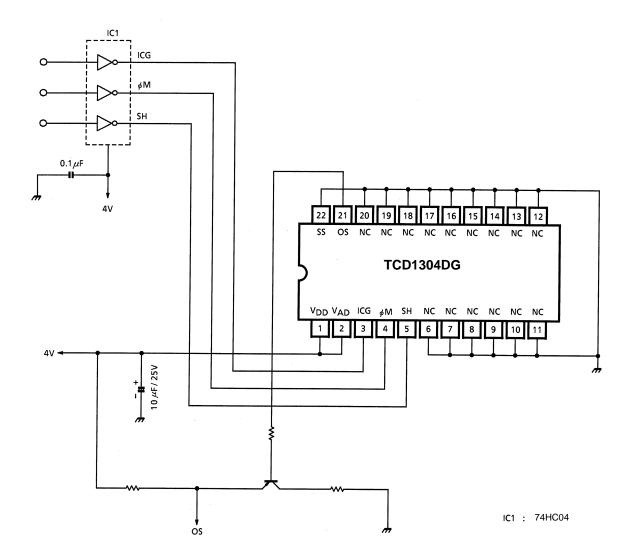








Typical Drive Circuit



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Cautions

1. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

CCD Image Sensor is protected against static electricity, but inferior puncture mode device due to static electricity is sometimes detected. In handing the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

- Prevent the generation of static electricity due to friction by making the work with bare hands or by putting a. on cotton gloves and non-charging working clothes.
- Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work b.
- Ground the tools such as soldering iron, radio cutting pliers of or pincer. C.
- lonized air is recommended for discharge when handling CCD image sensors.

It is not necessarily required to execute all precaution items for static electricity.

It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

2. Window Glass

The dust and stain on the glass window of the package degrade optical performance of CCD sensor. Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N2. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

3. Incident Light

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

Mounting on a PCB

This package is sensitive to mechanical stress.

TOSHIBA recommends using IC inserters for mounting, instead of using lead forming equipment. Since this package is not strong against mechanical stress, you should not reform the lead frame. We recommend to use an IC-inserter when you assemble to PCB.

Soldering

Soldering by the solder flow method cannot be guaranteed because this method may have deleterious effects on prevention of window glass soiling and heat resistance.

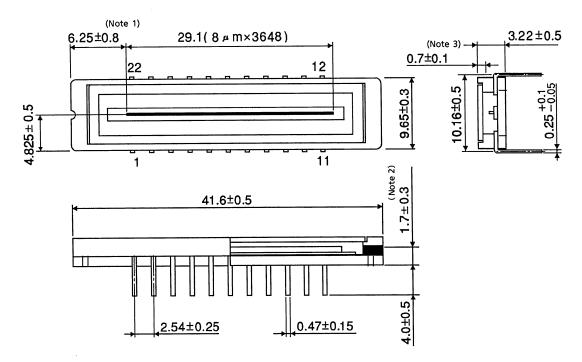
Using a soldering iron, complete soldering within three seconds for lead temperatures of up to 350°C.



Package Dimensions

WDIP22-G-400-2.54H

Unit: mm



- Note 1: Distance between the edge of the package and the first pixel (S1)
- Note 2: Distance between the top of chip and bottom of the package
- Note 3: Glass thickness (n = 1.5)



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